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# **RENESAS** R1LV1616HBG-I Series

Wide Temperature Range Version 16 M SRAM (1-Mword × 16-bit)

REJ03C0263-0100 Rev.1.00 Sep.21.2005

### Description

The R1LV1616HBG-I Series is 16-Mbit static RAM organized 1-Mword  $\times$  16-bit. R1LV1616HBG-I Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). It offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is packaged in 48-ball plastic FBGA for high density surface mounting.

#### Features

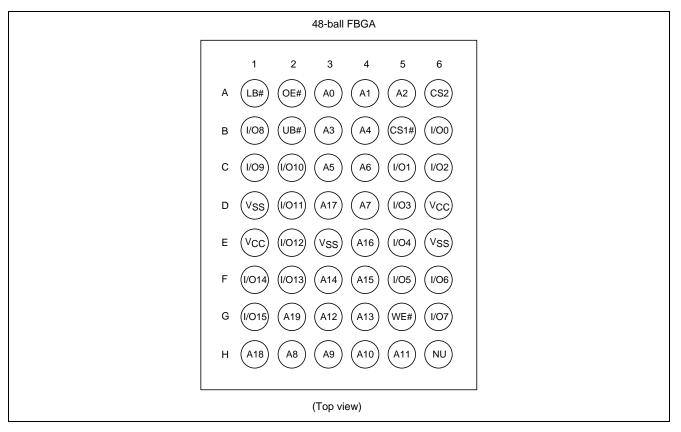
- Single 3.0 V supply: 2.7 V to 3.6 V
- Fast access time: 45/55 ns (max)
- Power dissipation:
  - Active: 9 mW/MHz (typ)
     Standby: 1.5 μW (typ)
- Completely static memory.
   No clock or timing strobe required
- Equal access and cycle times
- Common data input and output. — Three state output
- Battery backup operation.
- 2 chip selection for battery backup
- Temperature range: -40 to  $+85^{\circ}$ C

# **Ordering Information**

Type No.	Access time	Package
R1LV1616HBG-4SI 45 ns		48-ball plastic FBGA with 0.75 mm ball pitch
R1LV1616HBG-5SI	55 ns	PTBG0048HF (48FHJ)



# **Pin Arrangement**



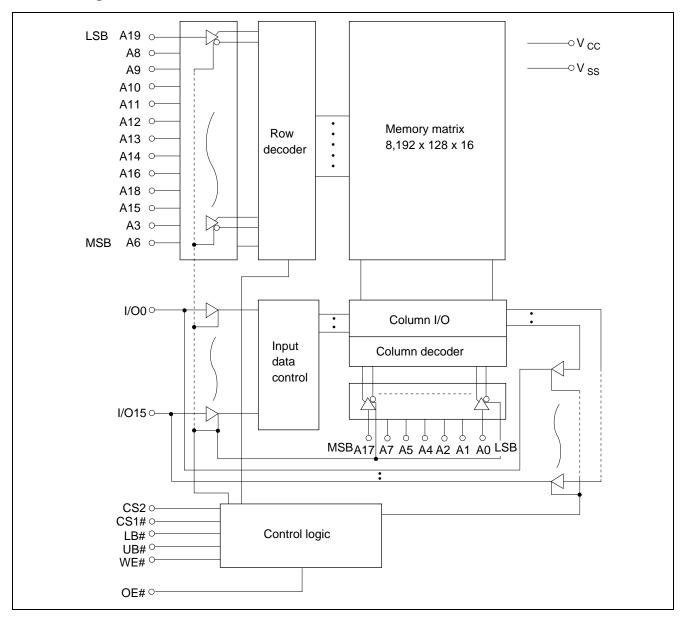
# **Pin Description**

Pin name	Function				
A0 to A19	Address input				
I/O0 to I/O15 Data input/output					
CS1# (CS1) Chip select 1					
CS2 Chip select 2					
WE# (WE)	Write enable				
OE# (OE)	Output enable				
LB# ( <del>LB</del> )	Lower byte select				
UB# ( <del>UB</del> )	Upper byte select				
V <sub>cc</sub>	Power supply				
V <sub>SS</sub>	Ground				
NU* <sup>1</sup>	Not used (test mode pin)				

Note: 1. This pin should be connected to a ground ( $V_{SS}$ ), or not be connected (open).



#### **Block Diagram**





# **Operation Table**

CS1#	CS2	WE#	OE#	UB#	LB# I/O0 to I/O7 I		I/O8 to I/O15	Operation
Н	×	×	×	×	×	High-Z High-Z		Standby
×	L	×	×	×	×	High-Z	High-Z	Standby
×	×	×	×	Н	Н	High-Z	High-Z	Standby
L	Н	Н	L	L	L	Dout	Dout	Read
L	Н	Н	L	Н	L	Dout	High-Z	Lower byte read
L	Н	Н	L	L	Н	High-Z	Dout	Upper byte read
L	Н	L	×	L	L	Din	Din	Write
L	Н	L	×	Н	L	Din	High-Z	Lower byte write
L	Н	L	×	L	Н	High-Z Din		Upper byte write
L	Н	Н	Н	×	×	High-Z	High-Z	Output disable

Note: H: V<sub>IH</sub>, L: V<sub>IL</sub>,  $\times$ : V<sub>IH</sub> or V<sub>IL</sub>

# **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Power supply voltage relative to V <sub>SS</sub>	V <sub>cc</sub>	–0.5 to +4.6	V
Terminal voltage on any pin relative to $V_{SS}$	V <sub>T</sub>	$-0.5^{*1}$ to V <sub>CC</sub> + $0.3^{*2}$	V
Power dissipation	PT	1.0	W
Storage temperature range	Tstg	-55 to +125	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Notes: 1.  $V_T$  min: -2.0 V for pulse half-width  $\leq$  10 ns.

2. Maximum voltage is +4.6 V.

### **DC Operating Conditions**

Parameter	Symbol	Min	Тур	Max	Unit	Note
Supply voltage	V <sub>CC</sub>	2.7	3.0	3.6	V	
	V <sub>SS</sub>	0	0	0	V	
Input high voltage	V <sub>IH</sub>	2.2	_	V <sub>CC</sub> + 0.3	V	
Input low voltage	V <sub>IL</sub>	-0.3	_	0.6	V	1
Ambient temperature range	Та	-40	_	+85	°C	

Note: 1.  $V_{IL}$  min: -2.0 V for pulse half-width  $\leq$  10 ns.



# **DC Characteristics**

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions
Input leakage current	I <sub>LI</sub>			1	μA	$Vin = V_{SS} to V_{CC}$
Output leakage current	I <sub>LO</sub>		_	1	μA	$CS1\# = V_{IH} \text{ or } CS2 = V_{IL} \text{ or}$
						$OE\# = V_{IH} \text{ or } WE\# = V_{IL} \text{ or}$
						$LB\# = UB\# = V_{IH}, V_{I/O} = V_{SS} \text{ to } V_{CC}$
Operating current	I <sub>CC</sub>	—	—	20	mA	$CS1\# = V_{IL}, CS2 = V_{IH},$
						Others = $V_{IH}/V_{IL}$ , $I_{I/O} = 0 \text{ mA}$
Average operating current	I <sub>CC1</sub>	—	22* <sup>1</sup>	35	mA	Min. cycle, duty = 100%,
	(READ)					$I_{I/O} = 0 \text{ mA}, \text{ CS1}\# = V_{IL}, \text{ CS2} = V_{IH},$
						WE# = $V_{IH}$ , Others = $V_{IH}/V_{IL}$
	I <sub>CC1</sub>		30* <sup>1</sup>	50	mA	Min. cycle, duty = 100%,
						$I_{I/O} = 0 \text{ mA}, \text{CS1}\# = V_{IL}, \text{CS2} = V_{IH},$
						$Others = V_{IH}/V_{IL}$
	I <sub>CC2</sub>	—	3* <sup>1</sup>	8	mA	Cycle time = $70 \text{ ns}$ , duty = $100\%$ ,
	(READ)					$I_{I/O} = 0 \text{ mA}, \text{ CS1}\# = V_{IL}, \text{ CS2} = V_{IH},$
						WE# = $V_{IH}$ , Others = $V_{IH}/V_{IL}$
						Address increment scan or decrement
	· .		00.1			scan
	I <sub>CC2</sub>		20* <sup>1</sup>	30	mA	Cycle time = 70 ns, duty = $100\%$ ,
						$I_{I/O} = 0$ mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ ,
						Others = $V_{IH}/V_{IL}$ Address increment scan or decrement
						scan
	I <sub>CC3</sub>		3* <sup>1</sup>	8	mA	Cycle time = 1 $\mu$ s, duty = 100%,
	ICC3		5	0	ШA	$I_{I/O} = 0 \text{ mA}, \text{ CS1}\# \le 0.2 \text{ V},$
						$CS2 \ge V_{CC} - 0.2 V$
						$V_{IH} \ge V_{CC} - 0.2 \text{ V}, V_{IL} \le 0.2 \text{ V}$
Standby current	I <sub>SB</sub>		0.1* <sup>1</sup>	0.5	mA	$CS2 = V_{\parallel}$
	I <sub>SB1</sub>		0.5* <sup>1</sup>	8	μA	$0 V \leq Vin$
	001				•	(1) 0 V ≤ CS2 ≤ 0.2 V or
						(2) $CS1\# \ge V_{CC} - 0.2 V$ ,
						$CS2 \ge V_{CC} - 0.2 V \text{ or}$
						(3) LB# = UB# $\ge$ V <sub>CC</sub> – 0.2 V,
						$CS2 \ge V_{CC} - 0.2 V$ ,
						CS1# ≤ 0.2 V
						Average value
Output high voltage	V <sub>OH</sub>	2.4			V	$I_{OH} = -1 \text{ mA}$
	V <sub>OH</sub>	$V_{CC}-0.2$	_		V	$I_{OH} = -100 \ \mu A$
Output low voltage	V <sub>OL</sub>		_	0.4	V	$I_{OL} = 2 \text{ mA}$
	V <sub>OL</sub>		_	0.2	V	I <sub>OL</sub> = 100 μA

Notes: 1. Typical values are at  $V_{CC}$  = 3.0 V, Ta = +25°C and not guaranteed.

# Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$ 

						(	,
Parameter	Symbol	Min	Тур	Max	Unit	Test conditions	Note
Input capacitance	Cin	—	_	8	pF	Vin = 0 V	1
Input/output capacitance	C <sub>I/O</sub>	—	_	10	pF	$V_{I/O} = 0 V$	1

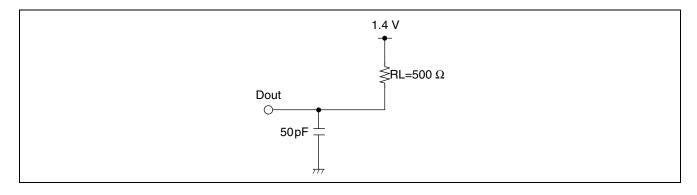
Note: 1. This parameter is sampled and not 100% tested.

# **AC Characteristics**

 $(Ta = -40 \text{ to } +85^{\circ}\text{C}, V_{CC} = 2.7 \text{ V to } 3.6 \text{ V})$ 

#### **Test Conditions**

- Input pulse levels:  $V_{IL} = 0.4 \text{ V}, V_{IH} = 2.4 \text{ V}$
- Input rise and fall time: 5 ns
- Input and output timing reference levels: 1.4 V
- Output load: See figures (Including scope and jig)





#### R1LV1616HBG-I Series

#### **Read Cycle**

			R1LV16	16HBG-I			
		-4	ISI	-5	SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	45	—	55		ns	
Address access time	t <sub>AA</sub>	_	45		55	ns	
Chip select access time	t <sub>ACS1</sub>	_	45		55	ns	
	t <sub>ACS2</sub>	_	45		55	ns	
Output enable to output valid	t <sub>OE</sub>	_	30		35	ns	
Output hold from address change	t <sub>OH</sub>	10	—	10		ns	
LB#, UB# access time	t <sub>BA</sub>		45		55	ns	
Chip select to output in low-Z	t <sub>CLZ1</sub>	10	—	10		ns	2, 3
	t <sub>CLZ2</sub>	10	—	10		ns	2, 3
LB#, UB# enable to low-Z	t <sub>BLZ</sub>	5	—	5		ns	2, 3
Output enable to output in low-Z	t <sub>OLZ</sub>	5	—	5		ns	2, 3
Chip deselect to output in high-Z	t <sub>CHZ1</sub>	0	20	0	20	ns	1, 2, 3
	t <sub>CHZ2</sub>	0	20	0	20	ns	1, 2, 3
LB#, UB# disable to high-Z	t <sub>BHZ</sub>	0	15	0	20	ns	1, 2, 3
Output disable to output in high-Z	t <sub>OHZ</sub>	0	15	0	20	ns	1, 2, 3

#### Write Cycle

			R1LV16				
		-4SI		-5SI			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t <sub>WC</sub>	45	—	55	—	ns	
Address valid to end of write	t <sub>AW</sub>	45	—	50	—	ns	
Chip selection to end of write	t <sub>CW</sub>	45	—	50	—	ns	5
Write pulse width	t <sub>WP</sub>	35	—	40		ns	4
LB#, UB# valid to end of write	t <sub>BW</sub>	45	—	50		ns	
Address setup time	t <sub>AS</sub>	0	—	0		ns	6
Write recovery time	t <sub>WR</sub>	0	—	0		ns	7
Data to write time overlap	t <sub>DW</sub>	25	—	25		ns	
Data hold from write time	t <sub>DH</sub>	0	—	0		ns	
Output active from end of write	t <sub>OW</sub>	5		5		ns	2
Output disable to output in high-Z	t <sub>OHZ</sub>	0	15	0	20	ns	1, 2
Write to output in high-Z	t <sub>WHZ</sub>	0	15	0	20	ns	1, 2

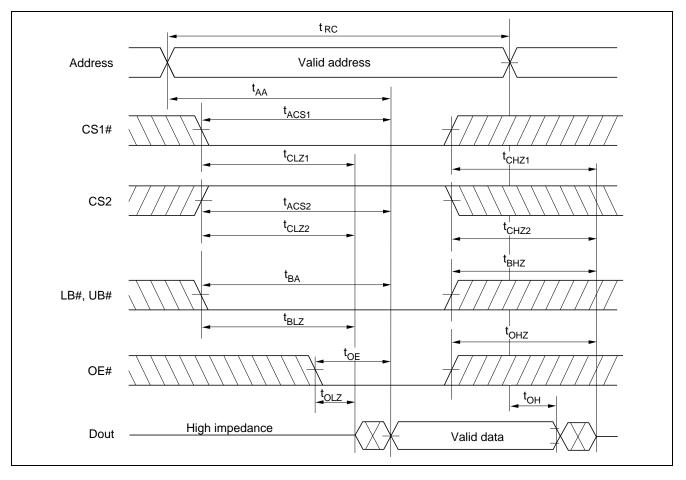
Notes: 1. t<sub>CHZ</sub>, t<sub>OHZ</sub>, t<sub>WHZ</sub> and t<sub>BHZ</sub> are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

- 2. This parameter is sampled and not 100% tested.
- At any given temperature and voltage condition, t<sub>HZ</sub> max is less than t<sub>LZ</sub> min both for a given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE# and a low LB# or a low UB#. A write begins at the latest transition among CS1# going low, CS2 going high, WE# going low and LB# going low or UB# going low. A write ends at the earliest transition among CS1# going high, CS2 going low, WE# going high and LB# going high or UB# going high. t<sub>WP</sub> is measured from the beginning of write to the end of write.
- 5.  $t_{CW}$  is measured from the later of CS1# going low or CS2 going high to the end of write.
- 6.  $t_{AS}$  is measured from the address valid to the beginning of write.
- 7. t<sub>WR</sub> is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle.



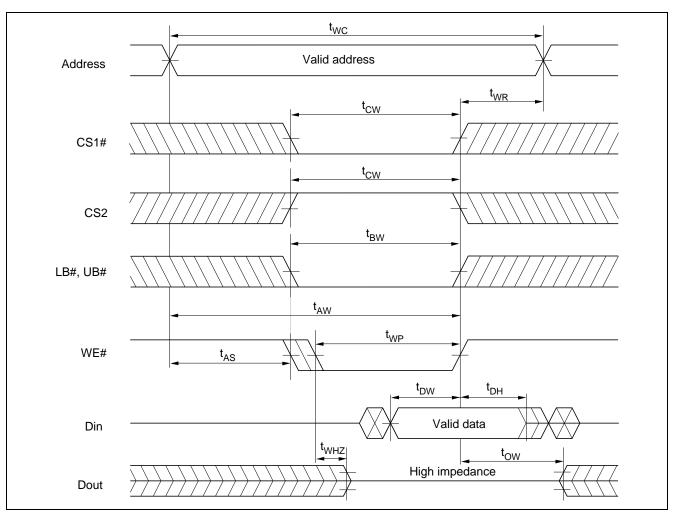
# **Timing Waveform**

# Read Cycle

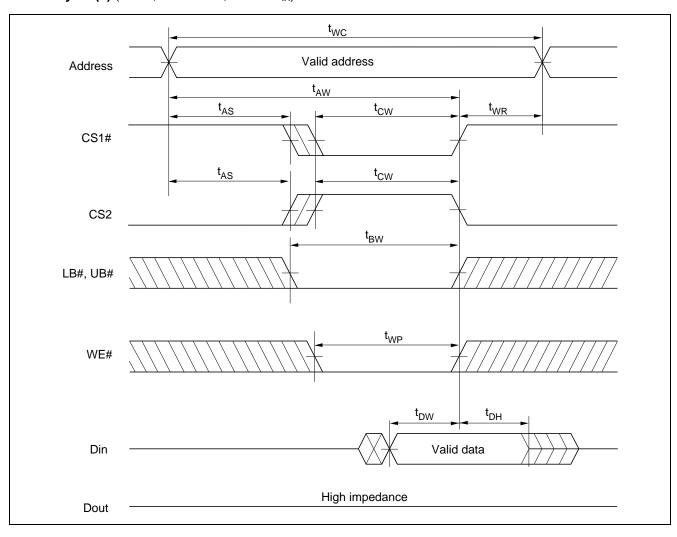




### Write Cycle (1) (WE# Clock)

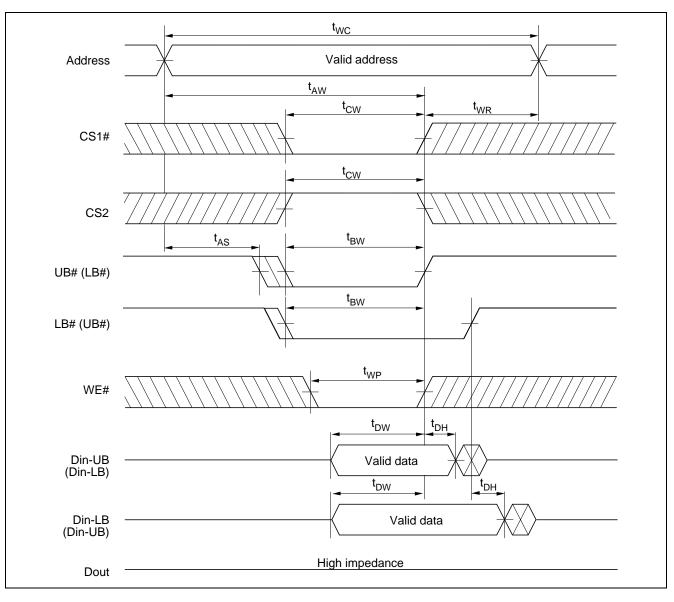






Write Cycle (2) (CS1#, CS2 Clock, OE# =  $V_{IH}$ )





### Write Cycle (3) (LB#, UB# Clock, $OE# = V_{IH}$ )



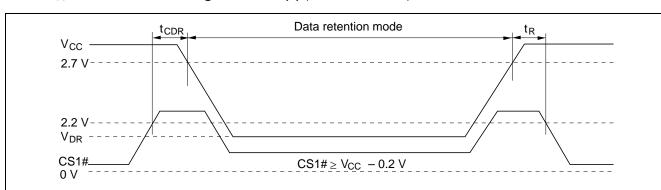
# Low $V_{\text{CC}}$ Data Retention Characteristics

						$(Ta = -40 \text{ to } +85^{\circ}\text{C})$
Parameter	Symbol	Min	Тур	Max	Unit	Test conditions* <sup>2</sup>
$V_{\rm CC}$ for data retention	V <sub>DR</sub>	1.5		3.6	V	$ \begin{array}{l} \mbox{Vin} \geq 0 \ \mbox{V} \\ (1) \ \ 0 \ \mbox{V} \leq CS2 \leq 0.2 \ \mbox{V} \ \ or \\ (2) \ \ CS2 \geq V_{CC} - 0.2 \ \ \ \ V, \\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $
Data retention current	I <sub>CCDR</sub>	_	0.5*1	8	μA	$\begin{split} & V_{CC} = 3.0 \; V, \; Vin \ge 0 \; V \\ & (1) \; 0 \; V \le CS2 \le 0.2 \; V \; or \\ & (2) \; CS2 \ge V_{CC} - 0.2 \; V, \\ & \; CS1\# \ge V_{CC} - 0.2 \; V \; or \\ & (3) \; LB\# = UB\# \ge V_{CC} - 0.2 \; V, \\ & \; CS2 \ge V_{CC} - 0.2 \; V, \\ & \; CS1\# \le 0.2 \; V \\ & \; Average value \end{split}$
Chip deselect to data retention time	t <sub>CDR</sub>	0	—	_	ns	See retention waveforms
Operation recovery time	t <sub>R</sub>	5		_	ms	1

Notes: 1. Typical values are at V\_{CC} = 3.0 V, Ta = +25 ^C and not guaranteed.

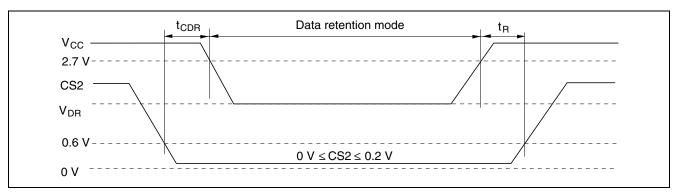
CS2 controls address buffer, WE# buffer, CS1# buffer, OE# buffer, LB#, UB# buffer and Din buffer. If CS2 controls data retention mode, Vin levels (address, WE#, OE#, CS1#, LB#, UB#, I/O) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be CS2 ≥ V<sub>CC</sub> – 0.2 V or 0 V ≤ CS2 ≤ 0.2 V. The other input levels (address, WE#, OE#, LB#, UB#, I/O) can be in the high impedance state.



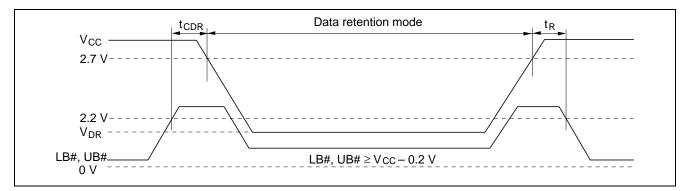


#### Low V<sub>CC</sub> Data Retention Timing Waveform (1) (CS1# Controlled)





#### Low V<sub>CC</sub> Data Retention Timing Waveform (3) (LB#, UB# Controlled)



### **Revision History**

#### R1LV1616HBG-I Series Data Sheet

Rev.	Date		Contents of Modification					
		Page	Description					
0.01	Apr. 29. 2005	_	Initial issue					
1.00	Sep. 21. 2005		Deletion of Preliminary					

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